

- standard size spring test probe for ICT FCT contacts

Suzhou Shengteng Electronic Co.Ltd is mainly produce spring test probe for PCB,ICT and FCT test.The most common test methods in the quality inspection of electronic assemblies are the In-Circuit Test (ICT), and the Functional Test (FCT).

About the ICT/FCT contacts the most common designs of test probes are shown as below. Most of them are compatible with other brands on the international market. If you didn't find the suitable size for you, please just call us - we assist you in direct consultation.

Series	Overall length	Barrel dia	Maximum travel	Recomm.travel	Current rating
SF-P11	24	ø1.01	4.0	2.6	2-3A
SF-P111	33.3	ø1.01	6.3	4.2	2-3A
SF-P100	33	ø1.36	6.4	4.2	2-3A
SF-P125	33.3	ø2.01	6.3	4.2	2-3A
SF-P156	33.4	ø2.36	6.3	4.2	2-3A

Spring test probe product pictures



Suzhou Shengteng Electronic Co.,Ltd factory show

